Amendments to the Specification:

Please replace paragraph 0081 with amended paragraph 0081 provided below:

[0081] A fixture assembly ~~(100, 102)~~ is presented. The fixture assembly includes a device interface assembly ~~(102)~~ for mating with a device under test and a tester interface assembly~~(100)~~ for mating with the device interface assembly ~~(102)~~ on one side and a tester on a second side. In the method and apparatus of the present invention, the device interface assembly ~~(102)~~ includes a probe field specific to a device under test and may be changed to accommodate a different device, without changing the tester interface assembly. The tester interface assembly ~~(100)~~ includes a custom electronic module ~~(400)~~ and a standardized electronic module ~~(410)~~, which are both coupled to a PCB interface ~~(300)~~ in the tester interface assembly ~~(100)~~. As such, both standardized and specialized test may be modified and changed without redesigning the tester interface assembly ~~(100)~~.

Clean copy of amended paragraph 0081:

[0081] A fixture assembly is presented. The fixture assembly includes a device interface assembly for mating with a device under test and a tester interface assembly for mating with the device interface assembly on one side and a tester on a second side. In the method and apparatus of the present invention, the device interface assembly includes a probe field specific to a device under test and may be changed to accommodate a different device, without changing the tester interface assembly. The tester interface assembly includes a custom electronic module and a standardized electronic module, which are both coupled to a PCB interface in the tester interface assembly. As such, both standardized and specialized test may be modified and changed without redesigning the tester interface assembly.

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